



32K x 16 Static RAM

Features

- 5.0V operation ($\pm 10\%$)
- High speed
— $t_{AA} = 12 \text{ ns}$
- Low active power
— 825 mW (max., 10 ns, "L" version)
- Very Low standby power
— 500 μW (max., "L" version)
- Automatic power-down when deselected
- Independent Control of Upper and Lower bytes
- Available in 400-mil SOJ

Functional Description

The CY7C1022 is a high-performance CMOS static RAM organized as 32,768 words by 16 bits. This device has an automatic power-down feature that significantly reduces power consumption when deselected.

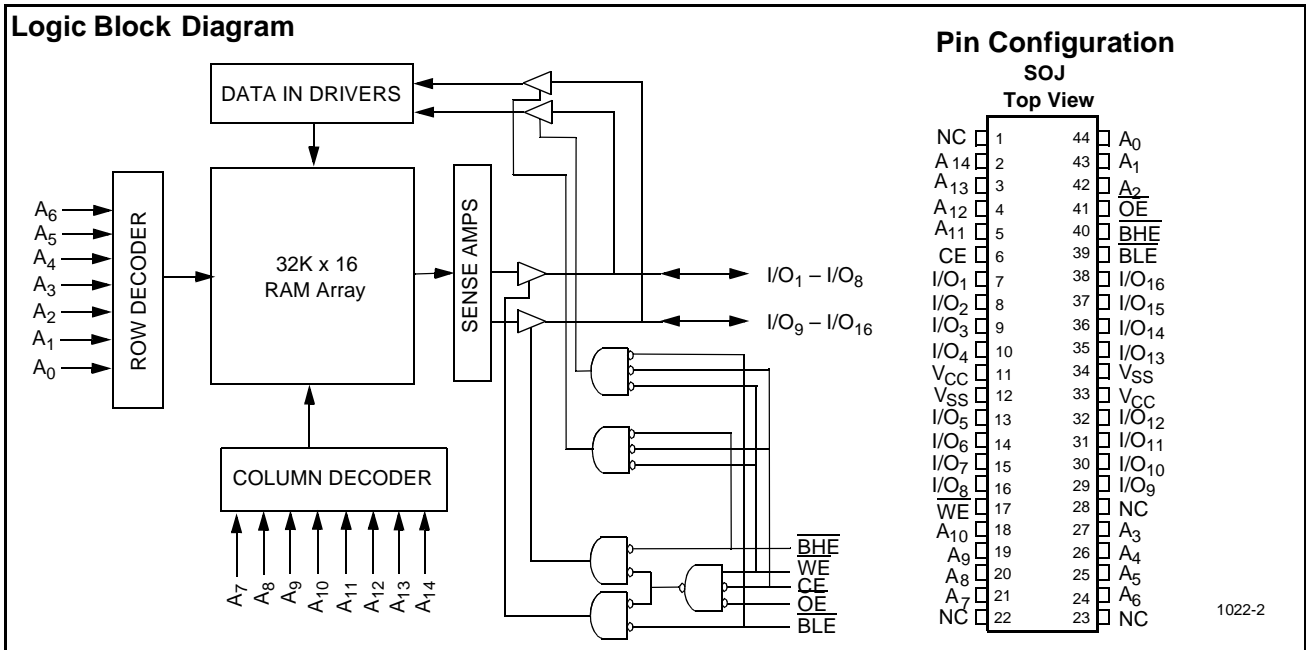
Writing to the device is accomplished by taking chip enable (CE) input HIGH and write enable (WE) input LOW. If byte low

enable ($\overline{\text{BLE}}$) is LOW, then data from I/O pins (I/O₁ through I/O₈), is written into the location specified on the address pins (A₀ through A₁₄). If byte high enable (BHE) is LOW, then data from I/O pins (I/O₉ through I/O₁₆) is written into the location specified on the address pins (A₀ through A₁₄).

Reading from the device is accomplished by taking chip enable (CE) HIGH and output enable (OE) LOW while forcing the write enable (WE) HIGH. If byte low enable (BLE) is LOW, then data from the memory location specified by the address pins will appear on I/O₁ to I/O₈. If byte high enable (BHE) is LOW, then data from memory will appear on I/O₉ to I/O₁₆. See the truth table at the back of this data sheet for a complete description of read and write modes.

The input/output pins (I/O₁ through I/O₁₆) are placed in a high-impedance state when the device is deselected (CE LOW), the outputs are disabled (OE HIGH), the BHE and BLE are disabled (BHE, BLE HIGH), or during a write operation (CE HIGH, and WE LOW).

The CY7C1022 is available in standard 400-mil-wide SOJ packages.



Selection Guide

| | 7C1022-12 | 7C1022-15 |
|-----------------------------------|-----------|-----------|
| Maximum Access Time (ns) | 12 | 15 |
| Maximum Operating Current (mA) | 170 | 160 |
| | L | 130 |
| Maximum CMOS Standby Current (mA) | 3 | 3 |
| | L | 0.1 |

Shaded areas contain advance information.



Maximum Ratings

(Above which the useful life may be impaired. For user guidelines, not tested.)

- Storage Temperature -65°C to +150°C
- Ambient Temperature with Power Applied..... -55°C to +125°C
- Supply Voltage on V_{CC} to Relative GND^[1] -0.5V to +7.0V
- DC Voltage Applied to Outputs in High Z State^[1]..... -0.5V to V_{CC} + 0.5V

- DC Input Voltage^[1] -0.5V to V_{CC} + 0.5V
- Current into Outputs (LOW) 20 mA

Operating Range

| Range | Ambient Temperature ^[2] | V _{CC} |
|------------|------------------------------------|-----------------|
| Commercial | 0°C to +70°C | 4.5V–5.5V |

Electrical Characteristics Over the Operating Range

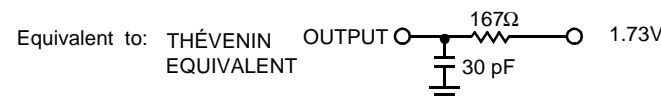
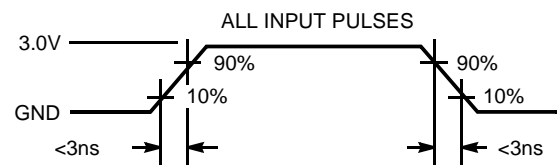
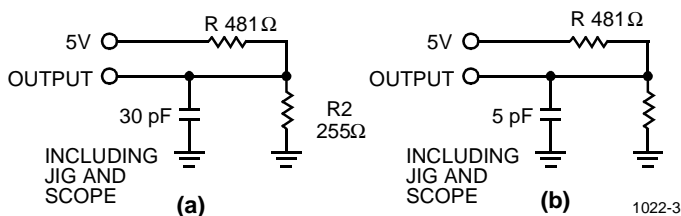
| Parameter | Description | Test Conditions | 7C1022-12 | | 7C1022-15 | | Unit |
|------------------|--|---|-----------|------|-----------|------|------|
| | | | Min. | Max. | Min. | Max. | |
| V _{OH} | Output HIGH Voltage | V _{CC} = Min., I _{OH} = -4.0 mA | 2.4 | | 2.4 | | V |
| V _{OL} | Output LOW Voltage | V _{CC} = Min., I _{OL} = 8.0 mA | | 0.4 | | 0.4 | V |
| V _{IH} | Input HIGH Voltage | | 2.2 | 6.0 | 2.2 | 6.0 | V |
| V _{IL} | Input LOW Voltage ^[1] | | -0.5 | 0.8 | -0.5 | 0.8 | V |
| I _{Ix} | Input Load Current | GND ≤ V _I ≤ V _{CC} | -1 | +1 | -1 | +1 | μA |
| I _{OZ} | Output Leakage Current | GND ≤ V _I ≤ V _{CC} , Output Disabled | -2 | +2 | -2 | +2 | μA |
| I _{CC} | V _{CC} Operating Supply Current | V _{CC} = Max., I _{OUT} = 0 mA, f = f _{MAX} = 1/t _{RC} | | 170 | | 160 | mA |
| | | | L | 140 | | 130 | |
| I _{SB1} | Automatic CE Power-Down Current —TTL Inputs | Max. V _{CC} , CE ≥ V _{IH} , V _{IN} ≥ V _{IH} or V _{IN} ≤ V _{IL} , f = f _{MAX} | | 20 | | 20 | mA |
| | | | L | 10 | | 10 | |
| I _{SB2} | Automatic CE Power-Down Current —CMOS Inputs | Max. V _{CC} , CE ≥ V _{CC} - 0.3V, V _{IN} ≥ V _{CC} - 0.3V, or V _{IN} ≤ 0.3V, f=0 | | 3 | | 3 | mA |
| | | | L | 0.1 | | 0.1 | mA |

Shaded area contains advance information.

Capacitance^[3]

| Parameter | Description | Test Conditions | Max. | Unit |
|------------------|--------------------|--|------|------|
| C _{IN} | Input Capacitance | T _A = 25°C, f = 1 MHz, V _{CC} = 5.0V | 8 | pF |
| C _{OUT} | Output Capacitance | | 8 | pF |

AC Test Loads and Waveforms



Notes:

1. V_{IL} (min.) = -2.0V for pulse durations of less than 20 ns.
2. T_A is the "instant on" case temperature.
3. Tested initially and after any design or process changes that may affect these parameters.

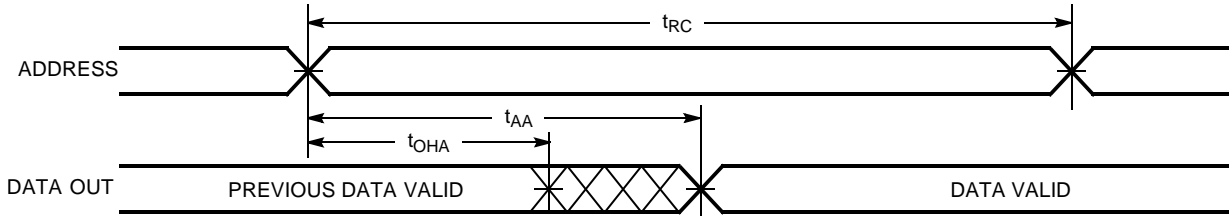


Switching Characteristics^[4] Over the Operating Range

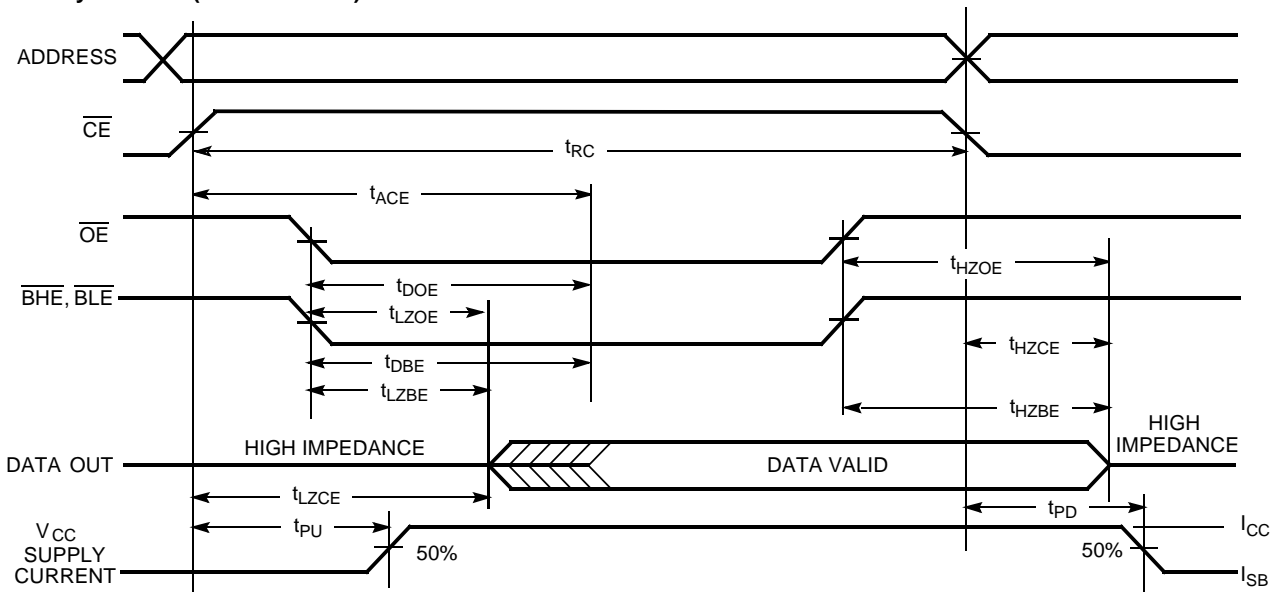
| Parameter | Description | 7C1022-12 | | 7C1022-15 | | Unit |
|----------------------------------|--|-----------|------|-----------|------|------|
| | | Min. | Max. | Min. | Max. | |
| READ CYCLE | | | | | | |
| t _{RC} | Read Cycle Time | 12 | | 15 | | ns |
| t _{AA} | Address to Data Valid | | 12 | | 15 | ns |
| t _{OHA} | Data Hold from Address Change | 3 | | 3 | | ns |
| t _{ACE} | CE HIGH to Data Valid | | 12 | | 15 | ns |
| t _{DOE} | \overline{OE} LOW to Data Valid | | 6 | | 7 | ns |
| t _{LZOE} | \overline{OE} LOW to Low Z | 0 | | 0 | | ns |
| t _{HZOE} | \overline{OE} HIGH to High Z ^[5, 6] | | 6 | | 7 | ns |
| t _{LZCE} | CE HIGH to Low Z ^[6] | 3 | | 3 | | ns |
| t _{HZCE} | CE LOW to High Z ^[5, 6] | | 6 | | 7 | ns |
| t _{PU} | CE HIGH to Power-Up | 0 | | 0 | | ns |
| t _{PD} | CE LOW to Power-Down | | 12 | | 15 | ns |
| t _{DBE} | Byte enable to Data Valid | | 6 | | 7 | ns |
| t _{LZBE} | Byte enable to Low Z | 0 | | 0 | | ns |
| t _{HZBE} | Byte disable to High Z | | 6 | | 7 | ns |
| WRITE CYCLE^[7] | | | | | | |
| t _{WC} | Write Cycle Time | 12 | | 15 | | ns |
| t _{SCE} | CE HIGH to Write End | 9 | | 10 | | ns |
| t _{AW} | Address Set-Up to Write End | 8 | | 10 | | ns |
| t _{HA} | Address Hold from Write End | 0 | | 0 | | ns |
| t _{SA} | Address Set-Up to Write Start | 0 | | 0 | | ns |
| t _{PWE} | \overline{WE} Pulse Width | 8 | | 10 | | ns |
| t _{SD} | Data Set-Up to Write End | 6 | | 10 | | ns |
| t _{HD} | Data Hold from Write End | 0 | | 0 | | ns |
| t _{LZWE} | \overline{WE} HIGH to Low Z ^[6] | 3 | | 3 | | ns |
| t _{HZWE} | \overline{WE} LOW to High Z ^[5, 6] | | 6 | | 7 | ns |
| t _{BW} | Byte enable to end of write | 8 | | 9 | | ns |

Notes:

4. Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5V, input pulse levels of 0 to 3.0V, and output loading of the specified I_{OL}/I_{OH} and 30-pF load capacitance.
5. t_{HZOE}, t_{HZBE}, t_{HZCE}, and t_{HZWE} are specified with a load capacitance of 5 pF as in part (b) of AC Test Loads. Transition is measured ±500 mV from steady-state voltage.
6. At any given temperature and voltage condition, t_{HZCE} is less than t_{LZCE}, t_{HZOE} is less than t_{LZOE}, and t_{HZWE} is less than t_{LZWE} for any given device.
7. The internal write time of the memory is defined by the overlap of CE HIGH, \overline{WE} LOW and BHE / BLE LOW. CE HIGH, \overline{WE} and BHE / BLE must be LOW to initiate a write, and the transition of these signals can terminate the write. The input data set-up and hold timing should be referenced to the leading edge of the signal that terminates the write.

Switching Waveforms
Read Cycle No.1 ^[8, 9]


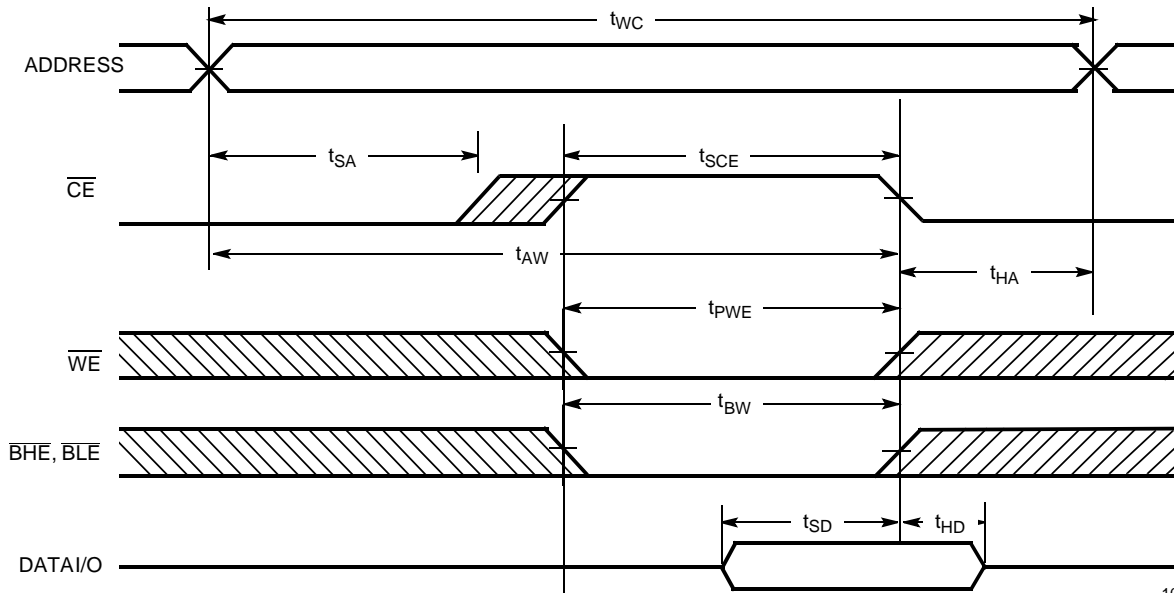
1022-5

Read Cycle No.2 (\overline{OE} Controlled) ^[9, 10]


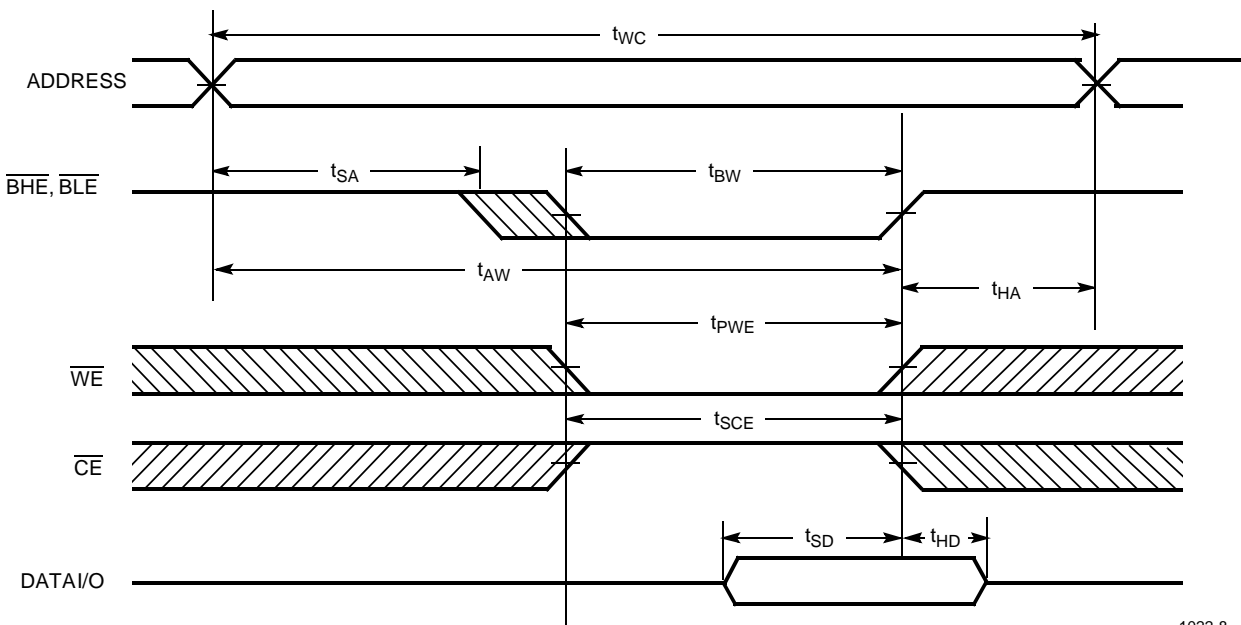
1022-6

Notes:

8. Device is continuously selected. \overline{OE} , \overline{CE} , \overline{BHE} and/or $\overline{BLE} = V_{IL}$.
9. \overline{WE} is HIGH for read cycle.
10. Address valid prior to or coincident with \overline{CE} transition HIGH.

Switching Waveforms (continued)
Write Cycle No. 1 ($\overline{\text{CE}}$ Controlled) ^[11, 12]


1022-7

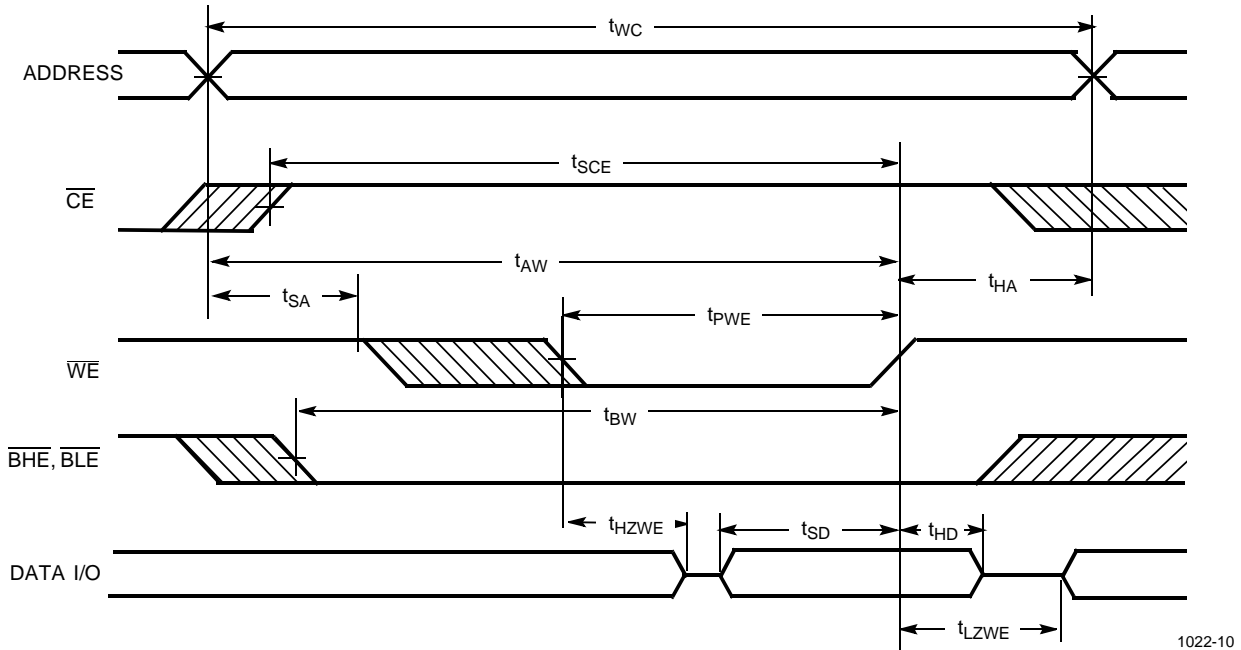
Write Cycle No. 2 ($\overline{\text{BLE}}$ or $\overline{\text{BHE}}$ Controlled)


1022-8

Notes:

11. Data I/O is high impedance if $\overline{\text{OE}}$ or $\overline{\text{BHE}}$ and/or $\overline{\text{BLE}} = V_{IH}$.
12. If CE goes LOW simultaneously with WE going HIGH, the output remains in a high-impedance state.

Switching Waveforms (continued)

Write Cycle No.3 (\overline{WE} Controlled, \overline{OE} LOW)


1022-10

Truth Table

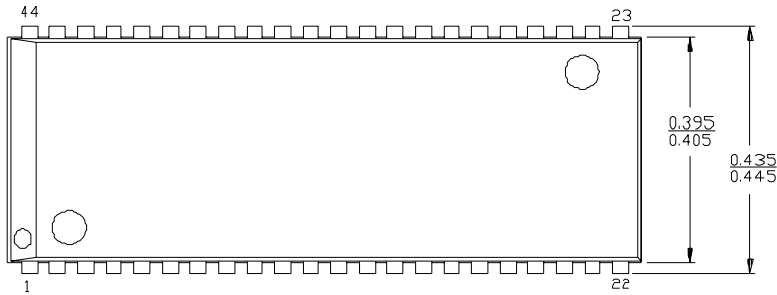
| \overline{CE} | \overline{OE} | \overline{WE} | \overline{BLE} | \overline{BHE} | $I/O_1 - I/O_8$ | $I/O_9 - I/O_{16}$ | Mode | Power |
|-----------------|-----------------|-----------------|------------------|------------------|-----------------|--------------------|----------------------------|----------------------|
| L | X | X | X | X | High Z | High Z | Power-Down | Standby (I_{SB}) |
| H | L | H | L | L | Data Out | Data Out | Read - All bits | Active (I_{CC}) |
| | | | L | H | Data Out | High Z | Read - Lower bits only | Active (I_{CC}) |
| | | | H | L | High Z | Data Out | Read - Upper bits only | Active (I_{CC}) |
| H | X | L | L | L | Data In | Data In | Write - All bits | Active (I_{CC}) |
| | | | L | H | Data In | High Z | Write - Lower bits only | Active (I_{CC}) |
| | | | H | L | High Z | Data In | Write - Upper bits only | Active (I_{CC}) |
| H | H | H | X | X | High Z | High Z | Selected, Outputs Disabled | Active (I_{CC}) |
| H | X | X | H | H | High Z | High Z | Selected, Outputs Disabled | Active (I_{CC}) |

Ordering Information

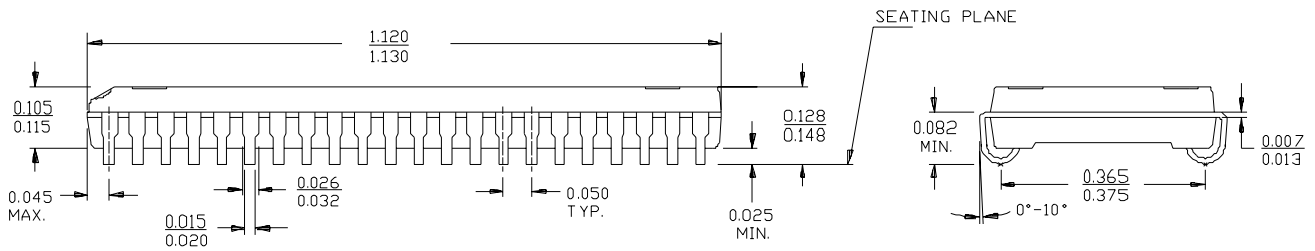
| Speed (ns) | Ordering Code | Package Name | Package Type | Operating Range |
|------------|---------------|--------------|------------------------------|-----------------|
| 12 | CY7C1022-12VC | V34 | 44-Lead (400-Mil) Molded SOJ | Commercial |

Package Diagram

44-Lead (400-Mil) Molded SOJ V34



DIMENSIONS IN INCHES MIN. MAX.





| Document Title: CY7C1022 32k x 16 Static RAM Data Sheet Document Number: 38-05090 | | | | |
|--|----------------|-------------------|------------------------|---|
| REV. | ECN NO. | Issue Date | Orig. of Change | Description of Change |
| ** | 110184 | 09/29/01 | SZV | Change from Spec number: 38-00636 to 38-05090 |